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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Ares Rosakis, et al. Art Unit: 2877
Serial No.: 10/766,512
Filed : January 27, 2004
Title : ANALYSIS AND MONITORING OF STRESSES IN EMBEDDED
LINES AND VIAS INTEGRATED ON SUBSTRATES

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Applicants call attention to the attached Information
Disclosure Statement and documents listed on form PTO-1449.

This filing is being made before the receipt of a first
Office action on the merits. No fee is required.

Consideration of the foregoing and enclosure plus the
return of a copy of the enclosed form PTO-1449 with the
Examiner's initials in the left column per MPEP 609 are
earnestly solicited along with an early action on the merits.

CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this
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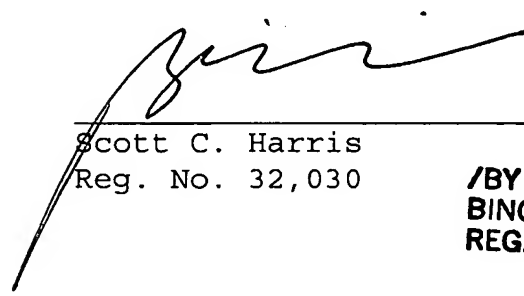
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Respectfully submitted,

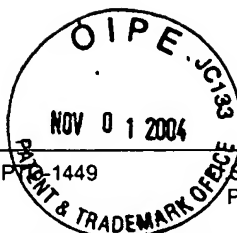
Date: October 28, 2004



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Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 06618-929001	Application No. 10/766,512
	Applicant Ares Rosakis, et al.		
	Filing Date January 27, 2004	Group Art Unit 2877	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6031611	2/29/2000	Rosakis, et al.			
	AB	6469788	10/22/2002	Boyd, et al.			
	AC	6513389	2/4/2003	Suresh, et al.			
	AD	6600565	7/29/2003	Suresh, et al.			
	AE	2004/0075825	4/22/2004	Suresh, et al.			
	AF	6781702	8/24/2004	Giannakopoulos, et al.			
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AR	Wikstrom, et al.; Thermoelastic analysis of periodic thin lines deposited on a substrate; 1999; Journal of the Mechanics and Physics of Solids, 47 (1999); pps 1113-1130
	AS	
	AT	
	AU	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	